An optimized self-test function for 64b/66b PCS

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Outline

- obvious BERT implementation
- reusing existing scrambler
- implementation details
- simulation results
- summary



the obvious way to do self-test



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Attributes of the obvious method

- + Pattern repeats every 0.21 seconds for quick, repeatable testing
- + Pattern is compatible with standard BERT equipment
- Test sequence is *not* compatible with other 64b/66b receivers not in self-test mode
- Extra gates are needed to build a completely independent BERT test mechanism
- Limited to 31 bit run-length. This run length occurs in normal 64b/66b data more often than once in 10¹⁰ bits so error floor is not well tested.
- Test pattern lacks sync headers which may affect receiver performance.



Strategy

- The 58 bit scrambler *is* already 90% of a BERT implementation, so why not reuse it to save gates?
- Use a normal scrambled 64b/66b idle frames as the self-test pattern
- Reset the scrambler state at start of test to a pattern computed to produce a 46 bit run-length
- Monitor scrambler state and reset both TX and RX scramblers to ensure a 0.21 second cycle time
- Look at errors in the *descrambled* Local Fault frames to estimate error rate



An optimized self-test method



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Implementation



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Counting errors

Under error-free conditions, the receiver descrambler will output the transmitted Local Fault pattern:

0x55 0x00 0x00 0x01 0x00 0x00 0x00 0x01

XOR-ing the actual received data bits with this expected pattern will give an error mask. The errors can be OR-ed together to compute a block error-rate, or added up and divided by 3 (the scrambler error-multiplication factor) to closely approximate the exact link BER.



Quality of test



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Summary

- + Proposed method optimizes gate count and complexity by reusing existing circuit
- + Proposed method tests to 46-bit run length to ensure absence of run-length-induced error floor
- Proposed method holds pattern length to ~2³¹-1 bits to ensure a rapid repeatable test result
- + Proposed test pattern is a normal 64b/66b Local Fault frame, and is gracefully handled by downstream circuitry
- Algorithm can be modified to produce: any peak run-length up to 57 bits shorter pattern length to alternately produce runs of *both* zeros *and* ones.

